

<b>FORM PTO-1449</b> U.S. Department of Commerce Patent and Trademark Office  List of Documents Cited by Applicant		Application No.:	10/615,842
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		First Named Inventor:	Oh
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		Examiner:	Phasge, Arun S.
		Attorney Docket No.:	421/170/8/2 CIP

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EXAMINER /Arun Phasge/ DATE CONSIDERED 10/09/2008

\*Examiner Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.